



Product data sheet

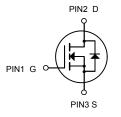
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N-Channel MOSFET

TO-252

Description

The AOD4144-MS uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

V_{DS} = 30V I_D =60 A

 $R_{DS(ON)} < 8.5 m\Omega @ V_{GS} = 10V$

Application

Battery protection

Load switch Uninterruptible power supply

Symbol Parameter		Rating	Units	
Vds	Drain-Source Voltage	30	V	
Vgs	Gate-Source Voltage	±20	V	
I₀@Tc=25°C	Continuous Drain Current, V _{GS} @ 10V ¹	60	А	
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ 10V ¹	40	А	
I _D @T _A =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	13.6	А	
I _D @T _A =70°C	Continuous Drain Current, V _{GS} @ 10V ¹	11.4	А	
Ідм	Pulsed Drain Current ²	110	А	
EAS	Single Pulse Avalanche Energy ³	57.8	mJ	
las	Avalanche Current	34	А	
P₀@Tc=25°C	Total Power Dissipation ⁴	41	W	
P _D @T _A =25°C	Total Power Dissipation ⁴	2.42	W	
Tstg	Storage Temperature Range	-55 to 175	°C	
TJ	Operating Junction Temperature Range	-55 to 175	°C	
Reja	Reja Thermal Resistance Junction-ambient (Steady State) ¹		°C/W	
Rejc	Thermal Resistance Junction-Case ¹	3.6	°C/W	

Absolute Maximum Ratings (TC=25°C unless otherwise specified)



AOD4144-MS	HF CRAS
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Symbol	Symbol Parameter Conditions		Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	30			V
∆BVbss/∆TJ	BVDSS Temperature Coefficient	Reference to 25°C , I _D =1mA		0.027		V/°C
		V _{GS} =10V , I _D =30A		7.5	8.5	
RDS(ON)	Static Drain-Source On-Resistance ²	V _{GS} =4.5V , I _D =15A		11	14	mΩ
VGS(th)	Gate Threshold Voltage		1.2	1.5	2.5	V
$\bigtriangleup V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	—V _{GS} =V _{DS} , I _D =250uA		-5.8		mV/°C
	Drain-Source Leakage Current	V_{DS} =24V , V_{GS} =0V , T_{J} =25°C				
IDSS		V _{DS} =24V , V _{GS} =0V , T _J =55°C			5	– uA
lgss	Gate-Source Leakage Current	V _{GS} =±20V , V _{DS} =0V			±100	nA
gfs	Forward Transconductance	V _{DS} =5V , I _D =30A		38		S
Rg	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		2.2	3.5	
Qg	Total Gate Charge (4.5V)			12.6	17.6	
Qgs	Gate-Source Charge	V _{DS} =15V , V _{GS} =4.5V , I _D =15A		4.2	5.9	nC
Q _{gd}	Gate-Drain Charge			5.1	7.1	
Td(on)	Turn-On Delay Time			4.6	9.2	
Tr	Rise Time			12.2	22	
Td(off)	Turn-Off Delay Time	I _D =15A		26.6	53	ns
Tf	Fall Time	_		8	16	
Ciss	Input Capacitance			1317	1843	
Coss	Output Capacitance			163	228	pF
Crss	Reverse Transfer Capacitance			131	183	
ls	Continuous Source Current ^{1,5}				55	A
lsм	Pulsed Source Current ^{2,5}	$-V_{G}=V_{D}=0V$, Force Current			110	A
Vsd	Diode Forward Voltage ²	V _{GS} =0V , I _S =1A , T _J =25°C			1.2	V
t _{rr}	Reverse Recovery Time			9.2		nS
	-	IF=30A , dl/dt=100A/µs ,		_		
Qrr	Reverse Recovery Charge	TJ=25℃		2		nC

Electrical Characteristics (TJ=25 °C, unless otherwise noted)

Note :

1 . The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.

2.The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%

3.The EAS data shows Max. rating . The test condition is V_{DD} =25V, V_{GS} =10V,L=0.1mH,I_{AS}=34A

4.The power dissipation is limited by 175°C junction temperature

5.The data is theoretically the same as I_{D} and I_{DM} , in real applications , should be limited by total power dissipation.





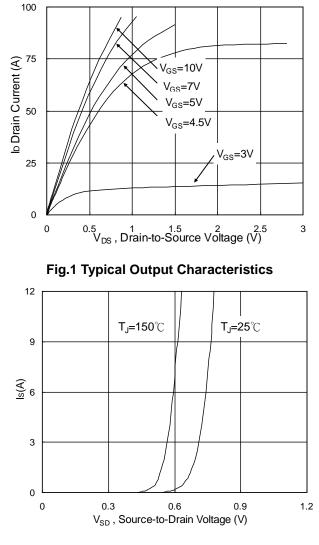


Fig.3 Forward Characteristics of Reverse

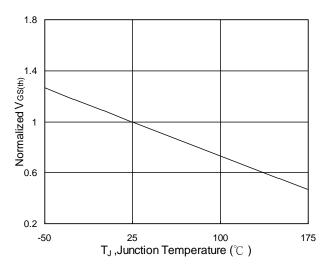


Fig.5 Normalized V_{GS(th)} vs. T_J

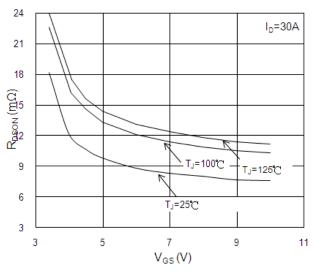


Fig.2 On-Resistance vs. G-S Voltage

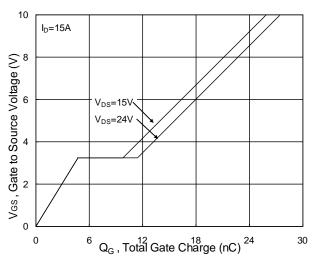


Fig.4 Gate-Charge Characteristics

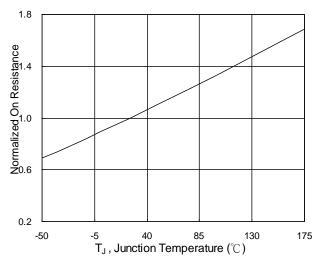
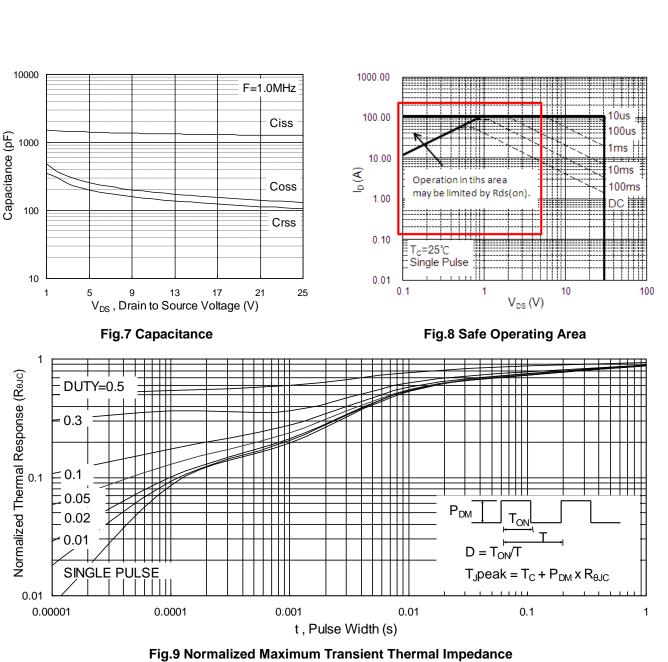
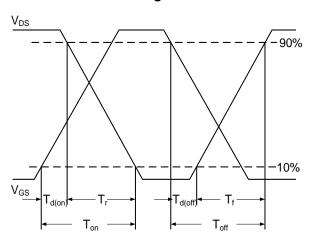
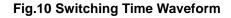


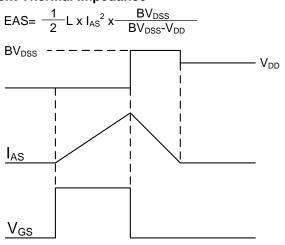
Fig.6 Normalized R_{DSON} vs. T_J











AOD4144-MS

Semiconductor

HF

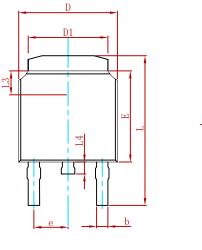
Compiance

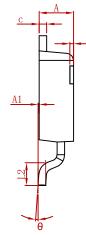
Fig.11 Unclamped Inductive Switching Waveform



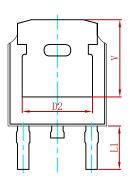


PACKAGE MECHANICAL DATA



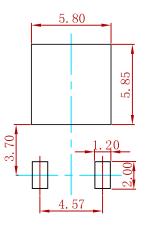


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Symbol	Dimensions	In Millimeters	Dimension	s In Inches
Symbol	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.635	0.770	0.025	0.030
С	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	4.830	REF.	0.190 REF.	
E	6.000	6.200	0.236	0.244
е	2.186	2.386	0.086	0.094
L	9.712	10.312	0.382	0.406
L1	2.900	REF.	0.114	REF.
L2	1.400	1.700	0.055	0.067
L3	1.600	REF.	0.063	REF.
L4	0.600	1.000	0.024	0.039
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.250	REF.	0.207	REF.

Suggested Pad Layout



Note:

1.Controlling dimension:in millimeters.

2.General tolerance:± 0.05mm.

3. The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
AOD4144-MS	TO-252	2500



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